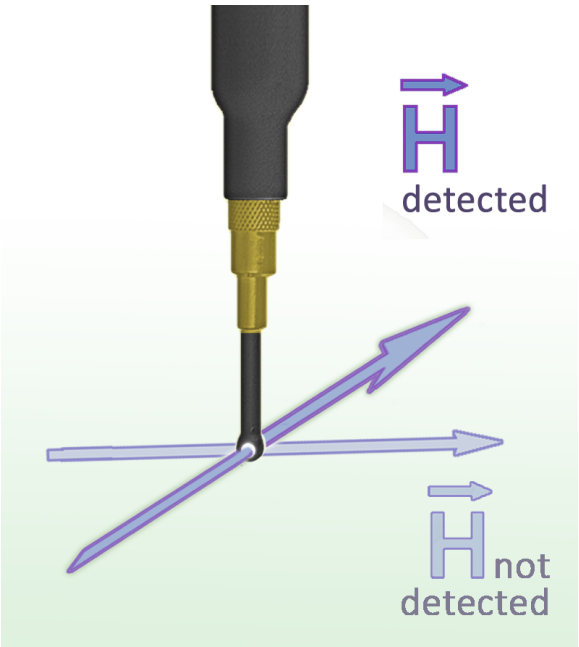
RFS-R 0.3-3

Scanner Probe 30 MHz up to 3 GHz



Short description

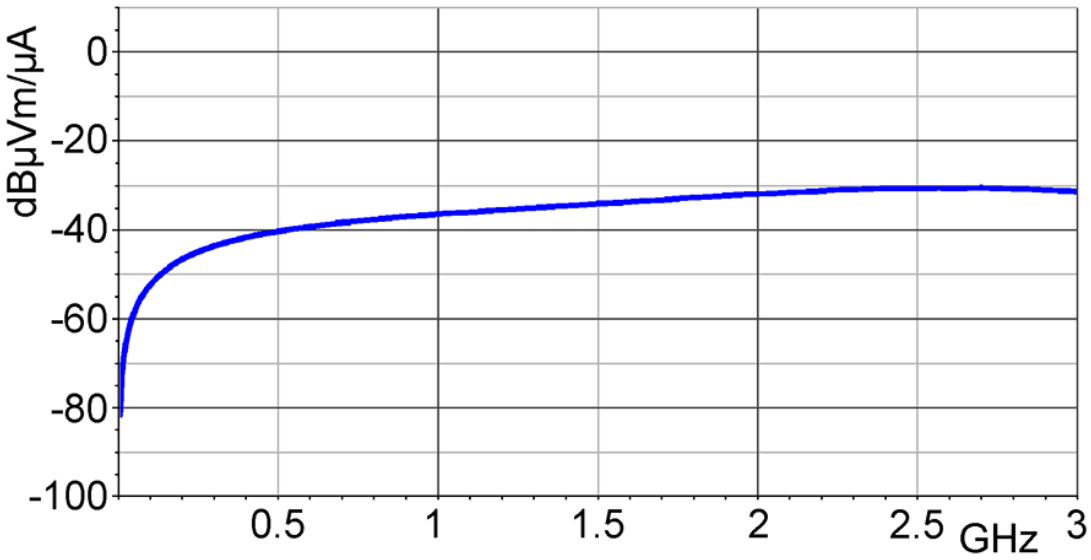
With its small probe head, the RFS-R 0.3-3 can measure magnetic fields in very high resolution. Thus even smallest components can be detected as interference sources. Furthermore, the small probe head is suitable for measurements at hard to reach spots, e.g. near IC pins.

The RFS-R 0.3-3 is a passive near-field scanner probe. The H-field probe is suitable for measurements close to the components in high magnetic electric field strenght range. The coil openings of the RF-R 0.3-3 probe are marked with white dots. Because of its small design measurements can be easily made at hard to reach spots, e.g. between components. The magnetic field scanner probe has a sheath current attenuation and is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω.

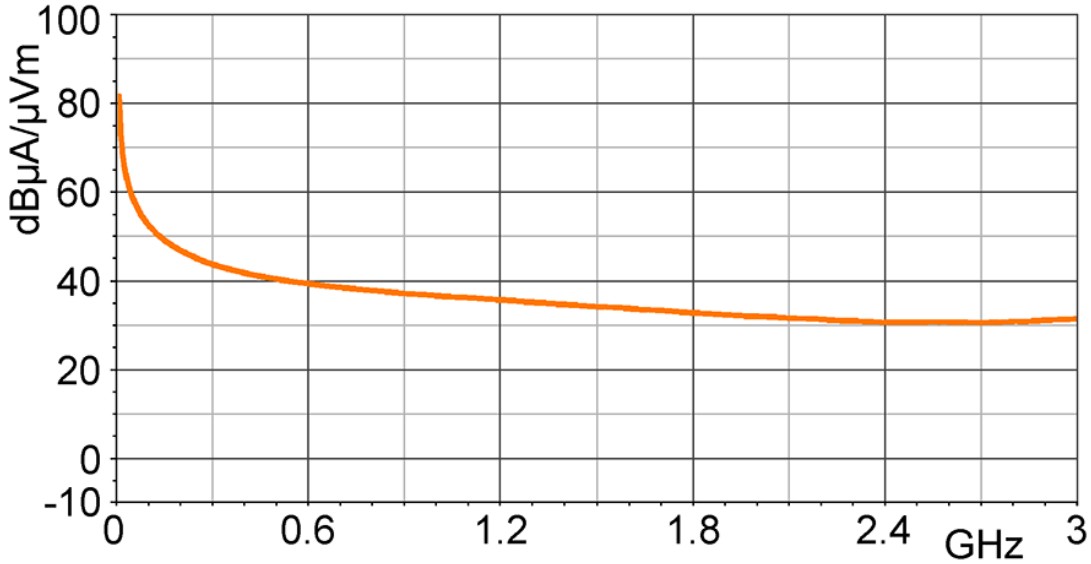
Technical parameters

Frequency range	30 MHz ... 3 GHz
Resolution	< 1 mm
Probe head dimensions:	Ø ≈ 2 mm
Connector - output	SMA, male, jack

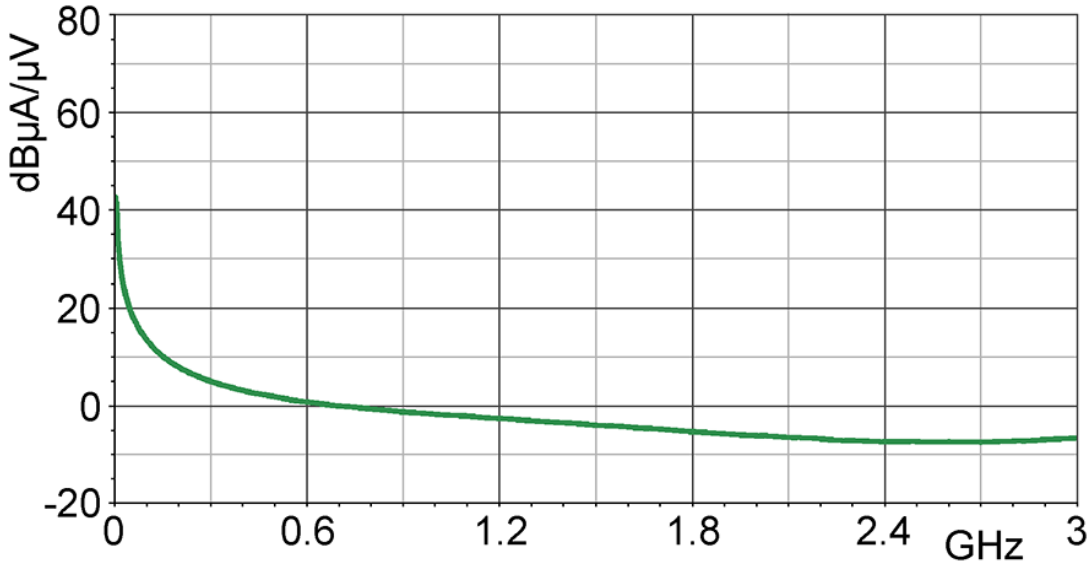
Frequency response [dBµV] / [dBµA/m]



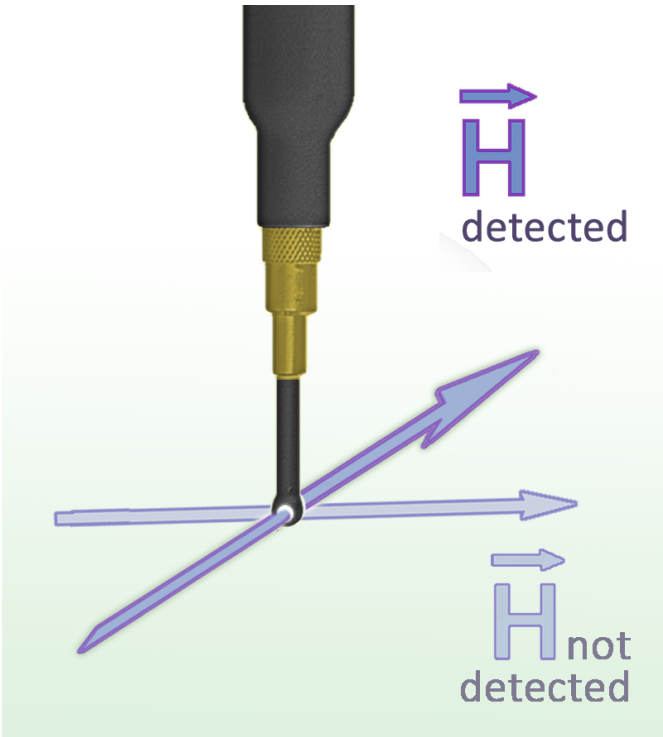
H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



Measuring principles



RFS-R 0.3-3

Scanner Probe 30 MHz up to 3 GHz